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Testing of Software and Communicating Systems

19th IFIP TC6/WG6.1 International Conference, TestCom 2007 7th International Workshop, FATES 2007 Tallinn, Estonia, June 26-29, 2007 Proceedings



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Preface

Testing is one of the most important techniques for validating the correctness of communicating and software systems. Triggered by the quest for improved quality of systems, and by the high and ever-increasing costs of making and executing the necessary tests, testing has evolved during the last two decades from an ad-hoc and under-exposed area of systems development to an important and active area, where a lot of research and development, in academia as well as in industry, is taking place. This evolvement is also reflected in an increasing number of testing conferences and workshops being regularly organized. Two of these, TestCom the 19th IFIP TC6/WG6.1 International Conference on Testing of Communicating Systems – and Fates the seventh International Workshop on Formal Approaches to Testing of Software, were jointly held in Tallinn, Estonia, June 27–29, 2007. In addition, FORTE, the 27th IFIP International Conference on Formal Methods for Networked and Distributed Systems, was also held in Tallinn during these dates, together thus forming a large event on testing, validation, and specification of software, communicating, and distributed systems.

The objective of TestCom/Fates 2007 was to offer a forum for researchers from academia as well as industry, developers, and testers to present, discuss, and learn about new approaches, theories, methods, and tools in the field of testing of software and communicating systems.

TestCom - Testing of Communicating Systems is an IFIP-sponsored series of international conferences, previously also called the International Workshop on Protocol Test Systems (IWPTS) or International Workshop on Testing of Communicating Systems (IWTCS). It is devoted to testing of communicating systems, including testing of communication protocols, services, distributed platforms, and middleware. The previous events were held in Vancouver, Canada (1988); Berlin, Germany (1989); McLean, USA (1990); Leidschendam, The Netherlands (1991); Montreal, Canada (1992); Pau, France (1993); Tokyo, Japan (1994); Evry, France (1995); Darmstadt, Germany (1996); Cheju Island, Korea (1997); Tomsk, Russia (1998); Budapest, Hungary (1999); Ottawa, Canada (2000); Berlin, Germany (2002); Sophia Antipolis, France (2003); Oxford, UK (2004); Montreal, Canada (2005); and New York, USA (2006).

FATES - Formal Approaches to Testing of Software is a series of workshops devoted to the use of formal methods in software testing. Previous events were held in Aalborg, Denmark (2001); Brno, Czech Republic (2002); Montreal, Canada (2003); Linz, Austria (2004); Edinburgh, UK (2005); and Seattle, USA (2006).

This volume contains the proceedings of TESTCOM/FATES 2007, the joint conference of TESTCOM and FATES. Out of 61 submitted papers, the Program Committee selected 24 papers for presentation at the conference. Together with the invited presentation by Antti Huima from Conformiq Software Ltd., Finland, they form the contents of these proceedings. The conference itself, in addition,

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contained another invited presentation, jointly with Forte, by Susanne Graf from Verimag (France), and presentations of work-in-progress papers, position papers, short experience reports, and tool demonstrations, which were separately published. A tutorial day preceded the main conference.

We would like to thank the numerous people who contributed to the success of TestCom/Fates 2007: the Steering Committee of IFIP for the Test-Com conference, the Program Committee and the additional reviewers for their support in selecting and composing the conference program, and the authors and the invited speakers for their contributions without which, of course, these proceedings would not exist. We thank Conformiq Software Ltd., CRIM, and Microsoft Research for their financial support and Springer for their support in publishing these proceedings. We acknowledge the use of EasyChair for the conference management and wish to thank its developers. Last, but not least, we thank the Institute of Cybernetics at Tallinn University of Technology and the Department of Computer Science of TUT, in particular, Juhan Ernits, Monika Perkmann, Jaagup Irve, Ando Saabas, Kristi Uustalu, and Tarmo Uustalu, for all matters regarding the local organization and for making TestCom/Fates 2007 run smoothly.

April 2007

Alexandre Petrenko Margus Veanes Jan Tretmans Wolfgang Grieskamp

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